EFFECT OF PROPAGATION ATTENUATION OF THIN FILM WAVEGUIDE ON OPTICAL THIN FILM LOSSES
I. THEORETICAL ANALYSIS

by

Liu Xu, Tang Jinfai, E. Pelletier
HUMAN TRANSLATION

NAIC-ID(RS)T-0761-94

28 April 1995

MICROFICHE NR: 95000256

EFFECT OF PROPAGATION ATTENUATION OF THIN FILM WAVEGUIDE ON OPTICAL THIN FILM LOSSES
I. THEORETICAL ANALYSIS

By: Liu Xu, Tang Jinfu, E. Pelletier

English pages: 12

Source: Guangxue Xuebao, Vol. 12, Nr. 4, April 1992; pp. 348-352

Country of origin: China
Translated by: Leo Kanner Associates
F33657-88-D-2188
Requester: NAIC/TAD/Orna E. Armstrong
Approved for public release; Distribution unlimited.

THIS TRANSLATION IS A RENDITION OF THE ORIGINAL FOREIGN TEXT WITHOUT ANY ANALYTICAL OR EDITORIAL COMMENT STATEMENTS OR THEORIES ADVOCATED OR IMPLIED ARE THOSE OF THE SOURCE AND DO NOT NECESSARILY REFLECT THE POSITION OR OPINION OF THE NATIONAL AIR INTELLIGENCE CENTER.

PREPARED BY:
TRANSLATION SERVICES
NATIONAL AIR INTELLIGENCE CENTER
WPAFB, OHIO

NAIC- ID(RS)T-0761-94

Date 28 April 1995
GRAPHICS DISCLAIMER

All figures, graphics, tables, equations, etc. merged into this translation were extracted from the best quality copy available.
EFFECT OF PROPAGATION ATTENUATION OF THIN FILM WAVEGUIDE ON OPTICAL THIN FILM LOSSES. I. THEORETICAL ANALYSIS

Liu Xu and Tang Jinfu, Department of Optical Instrumentation, Zhejiang University, Hangzhou 310027; and E. Pelletier, ENSPM, Marseille 13397, France

Abstract: Theoretical analysis of three fundamental deficiencies of optical thin films is studied: the effect of the extinction coefficient of the refractive index, surface roughness effects, and refractive index nonuniformity on the propagation attenuation of thin film waveguides. Based on different deficiencies in the propagation attenuation of different guide modes in optical thin films, the article presents a method of distinguishing absorption and scattering losses in thin films.

Key words: optical loss, thin film, waveguide, light scattering, light absorption.
I. Introduction

Many researchers in China and abroad are intensely researching thin film losses and have proposed many methods, such as the photometric method [1], heat measurement method [2], and methods of measuring scattered light with space distribution [3]. In traditional methods, however, the detection light beam illuminates thin film specimens from the outside; the film thickness restricts the action distance of the detecting light beam into the thin film medium. Thus, test sensitivity of the traditional method is limited. In contrast to the traditional approach, propagation of waveguide light in thin films expands the action distance of light into the thin film medium. The propagation properties of the waveguide can sufficiently indicate the structural form of the thin film medium, thus enhancing the test sensitivity of thin film losses. However, because of the complexity of waveguide propagation in a thin film, analysis becomes very complicated with respect to the losses. The purpose of this paper is to discuss the analysis of thin film absorption and scattering losses due to waveguide propagation attenuation.

II. Theoretical Analysis

Consider a single-layer thin film system: $n_s$ is the refractive index of its base, its surface is a medium with traces of roughness (marking as: $f_z(z)=x+d$); the thin film has a high refractive index $n_f$; its surface is a medium with traces of
roughness (marked as: \( f_c(z) = x \)) with \( k_f \) as the coefficient of light extinction for the surface; the refractive index of the thin film fluctuates randomly (marked as \( \Delta n_f(z) \)) along the z-direction, as shown in Fig. 1.

![Image of a single-layer optical thin film waveguide](image)

**Fig. 1.** Scheme of a single-layer optical thin film waveguide

Let us assume that the ratio between the roughness of two micro-rough boundary surfaces, the waveguide optical wavelength, and the thin film thickness are much smaller than 1; the random fluctuation amount \( \Delta n_f(z) \) of the refractive index is also much smaller than the thin film refractive index \( n_f \). In other words, \( \Delta n_f(z) \ll n_f \); moreover, these deficiencies are random functions of the variable \( z \), with the following statistical properties [4]:

\[
\begin{align*}
\langle f_s(z_1)f_s(z_2) \rangle &= \sigma_s \exp \left[-\frac{|z_1-z_2|}{\kappa_s}\right], \\
\langle f_s(z_1)f_s(z_2) \rangle &= \sigma_s \exp \left[-\frac{|z_1-z_2|}{\kappa_s}\right], \\
\langle \Delta n_f(z_1)\Delta n_f(z_2) \rangle &= \sigma_n \exp \left[-\frac{|z_1-z_2|}{\kappa_n}\right].
\end{align*}
\]

(1)

In the equation, \( \langle \rangle \) denotes the ensemble mean of the deficiencies along the z-direction; \( \sigma_s \) and \( \sigma_n \) denote the root-mean-square roughness of the corresponding boundaries;
$\sigma$ is the root-mean-square of the refractive index fluctuation of the thin film; $l_c$, $l_s$, and $l_n$ represent, respectively, the lengths of the corresponding deficiencies.

When a guided wave of a guide mode propagates in such a thin film structure, part of the guided wave energy is absorbed and converted to heat energy by the thin film. Part of the energy will generate a loss in the scattered light disturbance from the deficiencies, thus weakening the light intensity of the guided wave along the direction of propagation. Generally, $I=I_0e^{-\alpha z}$ indicates intensity variation of light intensity of the guided wave along the propagation direction $z$; alpha is the propagation attenuation coefficient of this guided wave. A concrete analysis is presented as follows:

1. Effect on propagation attenuation by absorption loss

Since there is absorption in the thin film, when the guided wave of a certain guide mode propagates in a thin film, thin film absorption attenuates the guided wave energy. The propagation constant $\zeta_{ss}=\beta_{s}-i\beta_{s}'$ of the guide mode can express this relationship well.

The guide mode equation of a thin film waveguide in the general form is [5]:

$$\zeta_{ss} = \zeta_{sm} = \frac{\eta_r \zeta_{em} - \zeta_{sm} \eta_m}{\zeta_{em} - \zeta_{sm}} = -\frac{1}{2} \ln \frac{\eta_r \zeta_{em} - \zeta_{sm} \eta_m}{\zeta_{em} - \zeta_{sm}} = -m \pi$$

(2)

In the equation, $\zeta_{ss} = (k_n^2 n_s^2 - \zeta_{sm}^2)^{1/2}$, $\zeta_{sm} = (\zeta_{sm}^2 - k_0^n n_s^2)^{1/2}$, $\zeta_{sm} = (\zeta_{sm}^2 - k_0^n n_s^2)^{1/2}$, $k_0 = 2\pi/\lambda_0$, $\eta_r = n_r^2$, and $(n_s - i k)^2$ (TM mode) or $\eta_{r} = 1$ (TE mode).
Based on the structure of thin film waveguides, the numerical method is applied to solve this complex transcendental equation, thus obtaining the complex propagation constant \( \beta_{jz} \) of various guide modes of this thin film. However, the virtual parts (\( \text{beta}'_v \)) of these propagation constants correspond to the propagation attenuation coefficients of the guide modes. Therefore, the propagation attenuation coefficient \( \alpha \) caused by the absorption loss is:

\[
\alpha = 2\beta_v \tag{3}
\]

2. Effect on propagation attenuation of scattering loss

The effects on guide mode propagation by trace-rough boundary surfaces of thin film waveguides, and random fluctuation of refractive index in the thin film is manifested in the form of light scattering loss.

By using the Maxwell equations, we derive that the wave equation of a thin film waveguide medium (as shown in Fig. 1) is:

\[
\begin{align*}
\nabla^2 \mathbf{E} + \mu_0 \omega^2 \varepsilon(x, z) \mathbf{E} &= 0, \\
\nabla^2 \mathbf{H} + \mu_0 \omega^2 \varepsilon(x, z) \mathbf{H} &= \frac{\nabla \times \mathbf{E} \times \nabla \times \mathbf{H}}{\varepsilon},
\end{align*}
\]

In the equation, \( \varepsilon(x, z) \) is the effective dielectric constant of the waveguide medium. For thin waveguides with micro-coarse boundary surface and fluctuation of refractive index, under the first-level approximation conditions, the effective dielectric constant is [6]:

\[
\begin{align*}
\varepsilon(x, z) &= \varepsilon^0(x) + \varepsilon^1(x, z), \\
\varepsilon^1(x, z) &= \varepsilon_0 \int_0^z \left\{ n^2 \delta(x - 0) - n^2 \delta(x - d) \right\} + \varepsilon_0 \int_0^z \left\{ n^2 \delta(x + d) - n^2 \delta(x + d) \right\}
\end{align*}
\]
+2e_0\Delta n_0(x)\theta[0-x]\theta[x+d], \quad (6)

\varepsilon(x) = \varepsilon_0_0\left\{n^2_0\theta[x-0]+n^2_0\theta[d-x]+n^2_0\theta[0-x]\theta[x+d]\right\}, \quad (7)

In the equations, \(\varepsilon_0_0\) and \(\mu_0\) represent, respectively, the dielectric constant and the magnetoconductivity in vacuo; \(\delta(x)\) is the Dirac; \(\theta[x]\) is the Heaviside function. It is shown that the waveguide deficiency can be indicated by equivalent additional dielectric constant \(\varepsilon(x,y)\) (additional source). These additional sources cause the scattering loss of guided wave propagation.

According to the optical theory of waveguides, a field of three modes of a thin film waveguide: air mode, base mode, and guide mode (the first two kinds are radiation modes) constitute a complete orthogonal base. Therefore in a waveguide, any field can be indicated by the linear combination of this orthogonal base \([7]\):

\[
\begin{align*}
E(x, y) &= \sum_{m=0}^\nu c_m(x)E_m(x, z) + \left\{g_r(x, \beta)E_r(x, z, \beta)d\beta, \right. \\
H(x, z) &= \sum_{m=0}^\nu b_m(x)H_m(x, z) + \left\{v_r(x, \beta)H_r(x, z, \beta)d\beta. \right. 
\end{align*}
\]  \quad (8)

In the equations \(E_n\) and \(H_n\) are the electric field and magnetic field of the various guide modes; \(E_r\) and \(H_r\) are the electric field and magnetic field of the radiation mode: \(c_m(z), \ b_m(z), \ g_r(z, \beta), \ v_r(z, \beta)\) are the to-be-determined radiation-value coefficients of the corresponding modes. The summations items in
the above equations are linear combinations of guide modes; the integration items are linear combinations of the radiation mode; this is the scattered optical field outside the waveguide; that is, the scattering loss. Therefore, to determine the scattering loss, the corresponding radiation-value coefficients \( g_r(z, \beta) \) and \( v_r(z, \beta) \) in the integration terms. By applying the orthogonal property of a mode in a waveguide [7], we have:

\[
\begin{align*}
\int_{-\infty}^{\infty} E(\beta) E^*(\beta') \, dx = \frac{\beta}{2\omega\mu_0} \delta(\beta - \beta'), \\
\int_{-\infty}^{\infty} H(\beta) H^*(\beta')/n^2 \, dx = \frac{\beta}{2\omega\varepsilon_0\mu_0} \delta(\beta - \beta'), 
\end{align*}
\]

(9)

In the equation, \( \beta \) and \( \beta' \) are the propagation constants of the mode. We can derive the radiation-value coefficient equations:

\[
\begin{align*}
\frac{\partial^2 g_r(z, \beta)}{\partial z^2} - 2i\beta \frac{\partial g_r(z, \beta)}{\partial z} &= \frac{-\omega\beta}{2} \left[ \int_{-\infty}^{\infty} \frac{e_1(x, z) E_i(x, z) E^*_i(x, z, \beta)}{\varepsilon_0(x, z)} \, dx \right] \\
\frac{\partial v_r(z, \beta)}{\partial z} - 2i\beta \frac{\partial v_r(z, \beta)}{\partial z} &= \frac{-\omega\beta}{2} \left[ \int_{-\infty}^{\infty} \frac{e_1(x, z) H_i(x, z) H^*_i(x, z, \beta)}{\varepsilon_0(x, z)} \, dx \right] \\
&\quad + \frac{e_1 \beta}{2\omega} \int_{-\infty}^{\infty} H^*_i(x, z, \beta) \cdot \frac{\nabla e_1(x, z)}{\varepsilon_0(x)} \, dx \\
&\quad \times \nabla \times H_i(x, z) e_y \, dz.
\end{align*}
\]

(10)

In the equations, it has been assumed that the fields of the initial guide mode are \( E_i(x, z) \) and \( H_i(x, z) \). The term with superscript * is the conjugate complex of the corresponding field; \( e_y \) is the unit vector along the \( y \) direction. From the solutions \( (g_r, v_r) \) in Eq. (10), when combined with the appropriate boundary conditions [8] of the deficiency section \( L \) of the thin film waveguide along the \( z \) direction, the scattering loss \( (\text{DELTAl}_4) \) of the waveguide can be derived. With further
derivation, the propagation attenuation $\alpha_{ij}$ caused by this scattering loss is:

$$\alpha_{ij} = \frac{\Delta I_i}{IL} = \frac{1}{L} \int_{-n_{ij}}^{n_{ij}} \langle \left| g^i(L, \beta) \right|^2 \rangle \frac{|\beta|}{p} d\beta. $$

(11)

In the equation, $p = (n_{ij}^2 k_0^2 - \beta^2)^{\frac{1}{2}}$. Here, the integration limits $n_{ij}k_0$ and $-n_{ij}k_0$ include two radiation modes. With respect to the TM mode, the $v^i_r(L, \text{beta})$ term should be used to replace $g^i_r(L, \text{beta})$ term in Eq. (11).

$\alpha_{ij}$ includes the surface scattering loss $\alpha_s$ caused by micro-coarse boundary surface, and the bulk scattering loss $\alpha_b$ caused by the fluctuating refractive index. In the general situation, to a thin film system with absorption loss and scattering loss, the overall propagation attenuation of the guided wave should be

$$\alpha = \alpha_0 + \alpha_1 = \alpha_a + \alpha_s + \alpha_b. $$

(12)

3. Analysis of Comprehensive Data

To quantitatively understand the propagation attenuation of a guide mode, in the article the properties of the propagation attenuation of a guide mode in thin films are numerically analyzed in three specific situations, with the results as shown in Figs. 2a, 2b, and 2c.

(a) The absorption loss $\alpha_a$ is the major one;

(b) The surface scattering loss $\alpha_s$ caused by surface coarseness is the major one; and

(c) The bulk scattering loss $\alpha_b$ caused by fluctuating
refractive index of the thin film is the major one.

Fig. 2. Attenuation coefficients of guided modes for a thin film waveguide with the following structure:
\( n_s=1, n_f=2.2, n_t=1.5, nd=10\lambda/4 (\lambda=632.8\text{nm}) \) under the following conditions:

(a) \( k_f=3.5\times10^{-5}; \sigma_s=\sigma_f=0.5\text{nm}; \sigma_t=0.001; L=L_L=1\mu m \)
(b) \( k_f=3\times10^{-5}; \sigma_s=\sigma_f=3.5\text{nm}; \sigma_t=0.001; L=L_L=1\mu m \)
(c) \( k_f=3\times10^{-5}; \sigma_s=\sigma_f=0.5\text{nm}; \sigma_t=0.01; L=L_L=1\mu m \)

By comparing the variation properties of attenuation in various deficiency situations with propagation angle theta of the guide mode, we can discover the following:

(1) Deficiency of a thin film is very sensitive to the propagation attenuation of a guide mode. The light extinction coefficient \( 10^{-5} \) and boundary surface coarseness of 2nm magnitude can be appreciably manifested in the propagation attenuation coefficient.
(2) Guide mode attenuation increases with mode level. When the absorption loss of the thin film is very small and can be neglected, the attenuation coefficients of the zero-level guide mode (TEO and TM0) are very small.

(3) In the situation of surface scattering and bulk scattering, the attenuation varies very rapidly with the propagation-angle variation $A_t(\theta)$. However, this variation is relatively moderate when the absorption loss is the major one. The function of scattering loss is very large to attenuation of a high-level guide mode. If the attenuation dependent on the propagation-angle variation $A_t(\theta)$ is extrapolated to $\theta = 90^\circ$, then $A_t(\theta)$ approaches a constant limit. Here, $A_t(\theta)$ is the variation type of propagation angle for the propagation attenuation coefficient $\alpha$ of various guide modes.

In the case of attenuation dependent on propagation-angle variation for the guide mode, the absorption and scattering losses in a thin film can be distinguished by propagation attenuation of different guide modes. Because in physics, when the $A_t(90^\circ)$ value corresponds to infinity thickness of the thin film, the propagation attenuation is at the zero-level waveguide of the guide mode. In this case, therefore, $A_t(90^\circ)$ does not have the effect of surface scattering loss, but is determined only by the light extinction coefficient $k_f$ and the fluctuating
value of the refractive index in the thin film. For thin films of optical media prepared with conventional evaporation technique, the light extinction coefficient of the refractive index is approximately within the range $10^{-5}$ to $10^{-3}$, correspondingly the propagation attenuation, when theta=90°, the attenuation is approximately in the range between 10 and 1000dB/cm (with respect to the 632.8nm wavelength). However, when the fluctuating value sigma$_h$ of the refractive index varies between 0.001 and 0.61, the corresponding attenuations are between 0.0006 and 0.06 dB/cm. Therefore, for this particular propagation angle, when the light extinction coefficient $k_f>10^{-6}$ for this thin film, the effect on attenuation due to bulk scattering is much smaller than absorption, so that the former can be neglected. Thus, by extrapolation the value of $A_t(90°)$ can be used to determine the light extinction coefficient $k_f$.

By using the light extinction coefficient $k_f$ of the thin film, and according to the above-mentioned theoretical conclusion, we can determine the attenuation alpha$_z$ due to absorption for various guide modes. Then, by comparing alpha$_z$ and the measured propagation attenuation alpha$_h$ of the guide mode, the attenuation of various guide modes corresponding to scattering loss can be determined:

$$\alpha_s = \alpha_m - \alpha_h,$$ (13)
Thus, the attenuation due to absorption loss and scattering loss of various guide modes can be distinguished.

The research was assisted and supported by colleagues of ENSPM at Marseille in France; the authors express their gratitude.

The first draft was received on 14 March 1991; the final revised draft was received for publication on 4 June 1991.

REFERENCES

DISTRIBUTION LIST

DISTRIBUTION DIRECT TO RECIPIENT

<table>
<thead>
<tr>
<th>ORGANIZATION</th>
<th>MICROFICHE</th>
</tr>
</thead>
<tbody>
<tr>
<td>BO85 DIA/RTS-2FI</td>
<td>1</td>
</tr>
<tr>
<td>C509 BALLOC509 BALLISTIC RES LAB</td>
<td>1</td>
</tr>
<tr>
<td>C510 R&amp;T LABS/AVEADCOM</td>
<td>1</td>
</tr>
<tr>
<td>C513 ARRADCOM</td>
<td>1</td>
</tr>
<tr>
<td>C535 AVRADCOM/TSARCOM</td>
<td>1</td>
</tr>
<tr>
<td>C539 TRASANA</td>
<td>1</td>
</tr>
<tr>
<td>Q592 FSTC</td>
<td>4</td>
</tr>
<tr>
<td>Q619 MSIC REDSTONE</td>
<td>1</td>
</tr>
<tr>
<td>Q008 NTIC</td>
<td>1</td>
</tr>
<tr>
<td>Q043 AFMIC-IS</td>
<td>1</td>
</tr>
<tr>
<td>E051 HQ USAF/INET</td>
<td>1</td>
</tr>
<tr>
<td>E404 AEDC/DOF</td>
<td>1</td>
</tr>
<tr>
<td>E408 AFWL</td>
<td>1</td>
</tr>
<tr>
<td>E410 AFUTC/IN</td>
<td>1</td>
</tr>
<tr>
<td>E429 SD/IND</td>
<td>1</td>
</tr>
<tr>
<td>P005 DOE/ISA/DDI</td>
<td>1</td>
</tr>
<tr>
<td>P050 CIA/OCR/ADD/SD</td>
<td>2</td>
</tr>
<tr>
<td>1051 AFIT/LDE</td>
<td>1</td>
</tr>
<tr>
<td>P090 NSA/CDB</td>
<td>1</td>
</tr>
<tr>
<td>2206 FSL</td>
<td>1</td>
</tr>
</tbody>
</table>

Microfiche Nbr: FTD95C000256
NAIC-ID(RS)T-0761-94